

<b>Notice of References Cited</b>	Application/Control No. 10/615,656	Applicant(s)/Patent Under Reexamination YOSHIZAWA, TAKASHI	
	Examiner Faye Francis	Art Unit 3728	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0201265 A1	10-2003	Lin, Tsong-Yow	220/254.3
*	B	US-6,170,651 B1	01-2001	Taormina, David M.	206/5
*	C	US-6,336,252 B1	01-2002	Bando, Ryosuke	16/307
*	D	US-6,398,017 B1	06-2002	Cafiero, Aldo	206/6
*	E	US-2003/0201268 A1	10-2003	Lin, Tsong-Yow	220/263
*	F	US-2002/0038804 A1	04-2002	Gourand, Thierry	220/835
*	G	US-6,588,624 B1	07-2003	Connors et al.	220/827
*	H	US-6,510,588 B2	01-2003	Eromaki, Marko	16/308
*	I	US-2003/0173369 A1	09-2003	Nikolaus et al.	220/830
*	J	US-5,067,625	11-1991	Numata, Masanori	220/827
*	K	US-2003/0106897 A1	06-2003	Zethoff et al.	220/264
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

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